Amendments to the Claims:

1-14. (Cancelled)

15. (Currently Amended) A method for testing memory, said method comprising:

performing a first test, wherein functional memory is tested;

repairing the functional memory by adding access to redundant elements, thereby providing repaired functional memory;

performing a second test, wherein the repaired functional memory is tested;

after repairing the functional memory and after testing the repaired functional memory, adding access to redundant memory not required for repair of the functional memory; and

after testing the repaired functional memory and then adding access to redundant memory not required for repair of the functional memory, performing a third test, wherein the redundant memory is tested.

16. (Previously Presented) A method as recited in claim 15, further comprising using repair information to repair the functional memory.

17. (Previously Presented) A method as recited in claim 15, wherein the step of adding access to redundant memory which is not required for the repair comprises forcing usage of redundant elements which are not needed to be used for repairing the functional memory.

18. (Previously Presented) A method as recited in claim 15, wherein the step of adding access to redundant memory which is not required for the repair comprises faking defects to remap good elements with redundant elements.

19. (Previously Presented) A method as recited in claim 15, further comprising checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

20. (Previously Presented) A method as recited in claim 15, wherein the step of adding access to redundant memory not required for repair of the functional memory comprises adding access to all remaining redundant memory, and wherein the step of performing a third test comprises testing all the remaining redundant memory.

21. (Currently Amended) A mode for testing memory, said mode comprising:

means for performing a first test, wherein functional memory is tested;

repairing the functional memory by adding access to redundant elements thereby providing repaired functional memory;

means for performing a second test, wherein the repaired functional memory is tested;

means for, after repairing the functional memory and after testing the repaired functional memory, adding access to redundant memory not required for repair of the functional memory; and

means for, after testing the repaired functional memory and then adding access to redundant memory not required for repair of the functional memory, performing a third test, wherein the redundant memory is tested.

22. (Previously Presented) A mode as recited in claim 21, further comprising means for using repair information to repair the functional memory.

23. (Previously Presented) A mode as recited in claim 21, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the functional memory.

24. (Previously Presented) A mode as recited in claim 21, further comprising means for faking defects to remap good elements with redundant elements.

25. (Previously Presented) A mode as recited in claim 21, further comprising means for checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

26. (Previously Presented) A mode as recited in claim 21, wherein the means for adding access to redundant memory not required for repair of the functional memory comprises means for adding access to all remaining redundant memory, and wherein the means for performing a third test comprises means for testing all the remaining redundant memory.